

PROCEEDINGS OF SPIE

***Technologies for
Synthetic Environments:
Hardware-in-the-Loop Testing XV***

**James A. Buford, Jr.
Robert Lee Murrer, Jr.**
Editors

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Contents

vii	<i>Conference Committee</i>
ix	<i>Introduction</i>

SESSION 1 SCENE SIMULATION: ENABLING TECHNOLOGIES

7663 02	Two-band DMD-based infrared scene simulator [7663-01] J. Rentz Dupuis, D. J. Mansur, R. Vaillancourt, T. Evans, D. Carlson, E. Schundler, OPTRA, Inc. (United States)
7663 03	Projection technologies for imaging sensor calibration, characterization, and HWIL testing at AEDC [7663-02] H. S. Lowry, M. F. Breeden, D. H. Crider, S. L. Steely, R. A. Nicholson, J. M. Labello, Aerospace Testing Alliance (United States)
7663 04	Effective and apparent temperature calculations and performance analysis of mid-wave infrared light emitting diodes for use in infrared scene projection [7663-03] E. M. Golden, R. J. Rapp, Air Force Research Lab. (United States)
7663 05	Recent advances in high density area array interconnect bonding for 3D integration [7663-04] J. M. Lannon, Jr., C. Gregory, M. Lueck, A. Huffman, D. Temple, RTI International (United States); A. J. Moll, W. B. Knowlton, Boise State Univ. (United States)
7663 06	LWIR NUC using an uncooled microbolometer camera [7663-05] J. LaVeigne, G. Franks, K. Sparkman, M. Prewarski, B. Nehring, S. McHugh, Santa Barbara Infrared, Inc. (United States)
7663 07	Component-level testing updates for the infrared polarized scene generator demonstrator [7663-06] P. S. Erbach, J. L. Pezzaniti, J. Reinhardt, D. B. Chenault, D. H. Goldstein, Polaris Sensor Technologies, Inc. (United States); H. S. Lowry, Aerospace Testing Alliance (United States)
7663 08	Two color IR LED array [7663-07] N. C. Das, U.S. Army Research Lab. (United States); F. Towner, Maxion Technologies, Inc. (United States)
7663 09	Photonic crystal scene projector development [7663-08] J. A. Wilson, Cyan Systems (United States); B. Burckel, Sandia National Labs. (United States); J. Caulfield, Cyan Systems (United States); S. Cogan, M. Massie, Nova Sensors (United States); R. Lamott, D. Snyder, R. Rapp, Air Force Research Lab. (United States)
7663 0A	Large format resistive array scene simulation validation testing and readiness [7663-09] J. Oleson, Oleson Convergent Solutions, LLC (United States); J. Cordell, D. Greer, T. Joyner, B. Woode, Naval Air Warfare Ctr. Aircraft Div. (United States)

- 7663 0C **Interband cascade resonant cavity surface emitting LEDs for 2D-array scene projectors** [7663-11]
J. L. Bradshaw, J. D. Bruno, K. M. Lascola, Maxion Technologies, Inc. (United States);
G. P. Meissner, U.S. Army Research Lab. (United States); J. T. Pham, F. J. Towner, Maxion
Technologies, Inc. (United States)

SESSION 2 HWIL IN SYSTEMS INTEGRATION TESTING

- 7663 0D **Ground-based IRCM testing** [7663-12]
D. Greer, ACETEF, NAVAIR (United States); M. Owen, AMEWAS, Inc. (United States)
- 7663 0E **Non-destructive missile seeker flight testing: HWIL in the sky** [7663-13]
J. Clements, U.S. Army AMRDEC (United States); J. Robinson, R. M. Robinson, Aegis
Technologies Group, Inc. (United States)
- 7663 0F **The synergistic roles of test and simulation in the life cycle of the Army Tactical Missile
System** [7663-14]
D. M. Curry, U.S. Army REDCOM (United States); G. Ricks, Precision Fires Rockets and Missiles
Project Office (United States); T. L. Thomas, U.S. Army REDCOM (United States)
- 7663 0G **Common hardware-in-the-loop development** [7663-15]
H. J. Kim, U.S. Army RDECOM/AMRDEC (United States); S. G. Moss, The Aegis Technologies
Group, Inc. (United States)

SESSION 3 FLIGHT MOTION SIMULATION TECHNOLOGY

- 7663 0H **Major discriminators in the facility design of infrared flight motion simulators** [7663-16]
R. W. Mitchell, Ideal Aerosmith, Inc. (United States)
- 7663 0I **Weighted least-squares based control for a four axis gimbal set** [7663-17]
D. R. Carter, P. Duffey, S. Bachorski, Acutronic USA, Inc. (United States); M. Kägi, Acutronic
Switzerland Ltd. (Switzerland); H. Havlicsek, Acutronic USA, Inc. (United States)

SESSION 4 HWIL ENABLING TECHNOLOGIES

- 7663 0J **Infrared transfer radiometer for broadband and spectral calibration of space chambers**
[7663-18]
T. M. Jung, A. C. Carter, S. I. Woods, S. G. Kaplan, R. U. Datla, National Institute of Standards
and Technology (United States)
- 7663 0K **MMW target and clutter characterization using the range instrumentation synthetic aperture
radar** [7663-19]
J. A. Ray, U.S. Army AMRDEC (United States); D. Barr, Simulation Technologies, Inc. (United
States)
- 7663 0L **Fast methods for computing scene raw signals in millimeter wave sensor simulations**
[7663-20]
R. F. Olson, U.S. Army AMRDEC (United States); T. M. Reynolds, H. D. Satterfield, Simulation
Technologies, Inc. (United States)

SESSION 5 SCENE GENERATION TECHNOLOGIES

- 7663 OM **Real-time maritime scene simulation** [7663-21]
E. TGouthas, C. L. Christie, L. Świerkowski, O. M. Williams, Defence Science and Technology Organisation (Australia)
- 7663 ON **Real-time scene generation infrared radiometry** [7663-22]
O. M. Williams, C. L. Christie, G. Shen, E. T. Gouthas, L. Świerkowski, Defence Science and Technology Organisation (Australia)
- 7663 OO **GPU based synthetic scene generation for maritime environments** [7663-24]
W. Keen, Air Force Research Lab. (United States); M. Tanner, L3 GS&ES (United States); C. Coker, Air Force Research Lab. (United States); D. Crow, Kinetics, Inc. (United States)
- 7663 OP **Exploiting current-generation graphics hardware for synthetic-scene generation** [7663-25]
M. A. Tanner, Air Force Research Lab. (United States); W. A. Keen, L3 GS&ES (United States)
- 7663 OQ **Power, pulse width, and repetition rate agile low-cost multi-spectral semi-active laser simulator** [7663-30]
J. K. O'Daniel, P. Young, Photodigm, Inc. (United States); E. Golden, R. Barton, D. Snyder, Air Force Research Lab. (United States)
- 7663 OR **A unification framework for best-of-breed real-time scene generation** [7663-27]
J. W. Morris, G. H. Ballard, U.S. Army AMRDEC (United States); D. E. Trimble, D. H. Bunfield, The Aegis Technologies Group, Inc. (United States); A. J. Mayhall, Dynamic Concepts, Inc. (United States)
- 7663 OS **Record breaking high-apparent temperature capability of LCoS-based infrared scene projectors** [7663-28]
J. R. Lippert, H. Wei, H. Yu, L. Li, Kent Optronics, Inc. (United States)

Author Index

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Welcome and Announcements
James A. Buford, Jr., Missile Defense Agency (United States)

- 1 Scene Simulation: Enabling Technologies
David B. Beasley, Optical Sciences Corporation (United States)
Naresh C. Das, Army Research Laboratory (United States)
Donald R. Snyder, Air Force Research Laboratory (United States)
John M. Lannon, Jr., RTI International (United States)

- 2 HWIL in Systems Integration Testing
James A. Buford, Jr., Missile Defense Agency (United States)
Brian K. Woode, Naval Air Warfare Center (United States)
Richard M. Robinson, The Aegis Technologies Group, Inc.
(United States)

- 3 Flight Motion Simulation Technology
Robert Lee Murrer, Jr., Millennium Engineering and Integration
Company(United States)
Robert W. Mitchell, Ideal Aerosmith, Inc. (United States)

Welcome and Announcements
James A. Buford, Jr., Missile Defense Agency (United States)

- 4 HWIL Enabling Technologies
Heard Lowry, Aerospace Testing Alliance (United States)
Scott B. Mobley, U.S. Army Aviation and Missile Research Development
and Engineering Center (United States)
- 5 Scene Generation Technologies
Charles F. Coker, Air Force Research Laboratory (United States)
James A. Annos, U.S. Navy (United States)
Dennis H. Bunfield, The Aegis Technologies Group, Inc. (United States)

Introduction

Beyond this page you will find the proceedings of the 15th conference of Technologies for Synthetic Environments: Hardware-in-the-Loop Testing. Our goal with this conference is to provide a broad spectrum of areas dealing with the science and art of hardware-in-the-loop simulation and testing.

In these proceedings you will find a refreshing variety of papers from flight motion simulator control schemes and test facility requirements, to innovations in scene generation, to infrared projector technology and characterization. Work continues with promising advancements in LED and photonic crystals for the next generation infrared projectors while GPU-based techniques emerge as an effective tool to bolster PC scene generation. Meanwhile, development continues on emitter arrays as they remain the standard in dynamic infrared scene projection.

We are eternally thankful to the authors and presenters who face competing interests for their time increasing demands of release authority. Many thanks also to Kathryn Stevens who was the motor behind the pleadings and urgings as deadlines came and went; without her support, this conference would not have been possible.

James A. Buford, Jr.
Robert Lee Murrer, Jr.

